

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/635,410	<b>Applicant(s)/Patent under Reexamination</b> VAN EGMOND ET AL.
	<b>Examiner</b> Tam M. Nguyen	<b>Art Unit</b> 1764

# **SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner